

12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20161027001 Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site Change Notification / Sample Request

Date: November 02, 2016

To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The proposed first ship date is indicated on page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services

20161027001 Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE CDCV304PW CDCV304PWR CDCV304PWG4 **CUSTOMER PART NUMBER**

null null null

Technical details of this Product Change follow on the next page(s).

PCN Number:	201	PCN Date: Nov. 2, 2016							
Title: Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site									
Customer Cont	act:	PCN Manager		Dept:			Quality Services		
Proposed 1 st Ship Date:		Feb. 2, 2017		Estimated Sample			Date provided at		
•		. 65/ _6_7	Availability			sample request.			
Change Type:	ita	Assembly							
Assembly S Design	ite	Assembly Process Electrical Specification					nbly Materials anical Specification		
Test Site			Shipping/Labeling		H		Process		
Wafer Bump	Site		mp Material		$\overline{\sqcap}$		r Bump Process		
Wafer Fab S			b Materials				/afer Fab Process		
		Part num	ber change						
		P	CN Details						
Description of	Change:								
Customers are a after this date w	dvised to plac ill be supporte	e their orders i ed with DMOS5		ure ful	fillr	nent. A	ny orders placed		
	ent (Disconti						ocation)		
Current Fab Site	Process	Wafer Diameter	New Fab Site	P		cess	Wafer Diameter		
ANAM-1	C10	200mm	DMOS5		C:	LO	200mm		
Reason for Cha	inge:								
Continuity of Su									
· · · · · · · · · · · · · · · · · · ·		ı, Fit, Functio	n, Quality or Reli	ability	/ (p	ositive	e / negative):		
None		<u>, , , </u>	, , ,				, <u>, , , , , , , , , , , , , , , , , , </u>		
Changes to pro	duct identifi	cation resulti	ng from this PCN	l:					
· ·									
Current:									
Chip Site		e Origin Code	Chip Site Count	ry Cod	e (1	211)	Chip Site City		
•		(20L)	·	· · · · · · · · · · · · · · · · · · ·					
ANAM-1		ANM	KOI	R		Bucheon-si			
New:									
	Chip Site	e Origin Code							
Chip Site		(20L)	Chip Site Count	ry Cod	e (2	21L)	Chip Site City		
DP1DM5 DM5		DM5	USA				Dallas		
<u> </u>									
Sample product shipping label (not actual product label)									
TEXAS INSTRUMENTS MADE IN: Malay 2DC: 20 MSL 2 /260C/1 MSL 1 /235C/UMOPT: ITEM: LBL: 5A (YSIA E YEAR SEAL DT		(1P) \$N (Q) 20 (31T) LC (4W) TK (P) (2P) REV. (20L) CSO (22L) ASO	00 0T: 39 Y(1T)	(V)	D) 03 0047MI 52348	A 3SI2 3317 :USA		
Product Affected:									

CDCV304PWR

CDCV304PWG4

CDCV304PW

CDCV304PWRG4

Qualification Report

CDCV304: Qualification of alternative FAB (DMOS5)

Approve Date 04-Dec-2015

Product Attributes

Attributes	Qual Device: CDCV304	QBS Product Reference CDCV304	QBS Process Reference: SN74AVC16T245DGGR	QBS Package Reference: CDCVF2505PW	QBS Package Reference: LMV324IPWR	QBS Package Reference: RC4558PWR	QBS Package Reference: SN0508073PW
Wafer Fab Supplier	DMOS5	DMOS5	CFAB	ANAM-1	FFAB	SFAB	MLA
Wafer Process	33C10	33C10	33C10	33C10	BCB	JI-SLM	LBC4X
Assembly Site	MLA	MLA	MLA	MLA	ASE SHANGHAI	MLA (TIM)	MLA
Package Family	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CDCV304	QBS Product Reference CDCV304	QBS Process Reference: SN74AVC16T245D GGR	QBS Package Reference: CDCVF2505PW	QBS Package Reference: LMV324IPWR	QBS Package Reference: RC4558PWR	QBS Package Reference: SN0508073PW
AC	Autoclave 121C	96 Hours	-	1/77/0	3/231/0	3/231/0	-	1/77/0	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	-	Pass	Pass	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	3/231/0	-	2/154/0	1/77/0	-
HAST	Biased HAST, 130C/85%RH	192 Hours					2/154/0		
HBM	ESD - HBM	2500 V	1/3/0	1/3/0	3/9/0	-	-	-	-
CDM	ESD - CDM	1000 V	1/3/0	1/3/0	3/9/0	-	-	-	-
HTSL	High Temp. StorageBake, 150C	1000 Hours	-		-	-	-	-	-
HTSL	High Temp. StorageBake, 170C	420 Hours	-		3/231/0	3/231/0	1/77/0	-	3/231/0
HTOL	High Temp Operating Life, 150C	300 Hours			3/231/0	-	-	-	-
LU	Latch-up	(per JESD78)	1/6/0		3/18/0	-	-	-	-
TC	Temperature Cycle, -55/125C	700 Cycles	-		-	-	-	-	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	3/231/0	3/231/0	-	1/77/0	3/231/0
TS	Thermal Shock, -65/150C	500 Cycles	-			3/231/0	-	-	3/231/0
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-		-	-	1/77/0	-	-
WBP	Bond Strength	Wires	-		3/228/0	-	2/154/0	1/76/0	-
MQ	Manufacturability	(per mfg. Site specification)	Pass	Pass					

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

⁻ QBS: Qual By Similarity - Qual Device CDCV304 is qualified at LEVEL1-260C